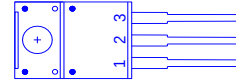
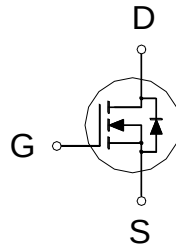


PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
200V	150m Ω	18A



1: GATE
2: DRAIN
3: SOURCE



ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		V_{DS}	200	V
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current	$T_C = 25^\circ\text{C}$	I_D	18	A
	$T_C = 100^\circ\text{C}$		7	
Pulsed Drain Current ¹		I_{DM}	30	
Avalanche Current		I_{AS}	11	
Avalanche Energy	$L = 1\text{mH}$	E_{AS}	61	mJ
Power Dissipation	$T_C = 25^\circ\text{C}$	P_D	42	W
	$T_C = 100^\circ\text{C}$		17	
Junction & Storage Temperature Range		T_J, T_{stg}	-55 to 150	$^\circ\text{C}$

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient	$R_{\theta JA}$		62.5	$^\circ\text{C} / \text{W}$
Junction-to-Case	$R_{\theta JC}$		3	

¹Pulse width limited by maximum junction temperature.

ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

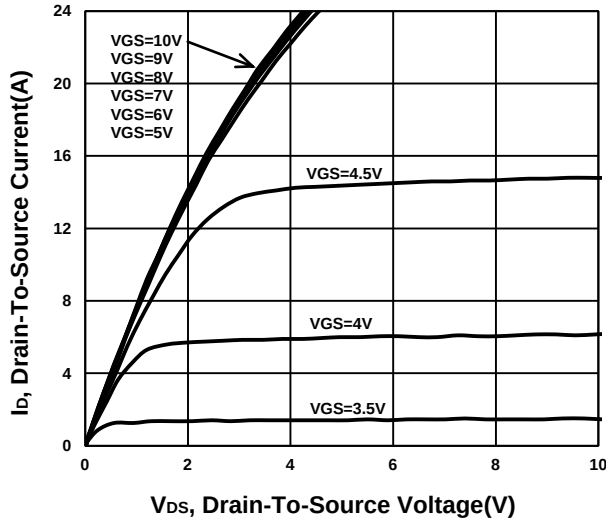
PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	200			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	1	2	3	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 20V$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 200V, V_{GS} = 0V$			1	μA
		$V_{DS} = 160V, V_{GS} = 0V, T_J = 125^\circ C$			10	
Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 4.5V, I_D = 9A$		175	195	m Ω
		$V_{GS} = 10V, I_D = 9A$		117	150	
Forward Transconductance ¹	g_{fs}	$V_{DS} = 10V, I_D = 9A$		15		S

DYNAMIC						
Input Capacitance	C _{iss}	V _{GS} = 0V, V _{DS} = 25V, f = 1MHz		811		pF
Output Capacitance	C _{oss}			137		
Reverse Transfer Capacitance	C _{rss}			19		
Total Gate Charge ²	Q _{g(VGS=10V)}	V _{DS} = 160V , I _D =18A		25		nC
	Q _{g(VGS=4.5V)}			13		
Gate-Source Charge ²	Q _{gs}			3		
Gate-Drain Charge ²	Q _{gd}			10		
Turn-On Delay Time ²	t _{d(on)}	V _{DS} = 100V , I _D ≅ 18A, V _{GS} = 10V, R _{GEN} =25Ω		21		nS
Rise Time ²	t _r			140		
Turn-Off Delay Time ²	t _{d(off)}			183		
Fall Time ²	t _f			133		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T _j = 25 ° C)						
Continuous Current	I _S				18	A
Forward Voltage ¹	V _{SD}	I _F = 18A, V _{GS} = 0V			1	V
Diode Reverse Recovery Time	t _{rr}	I _F = 18A, dI/dt=100A/μs		130		nS
Diode Reverse Recovery Charge	Q _{rr}			0.67		uC

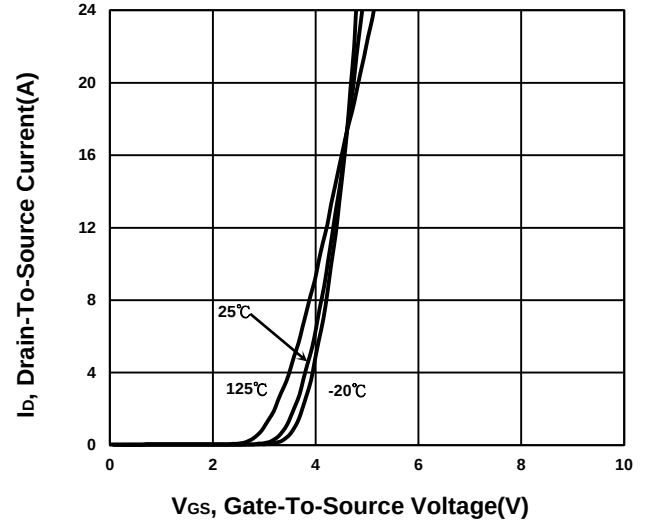
¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

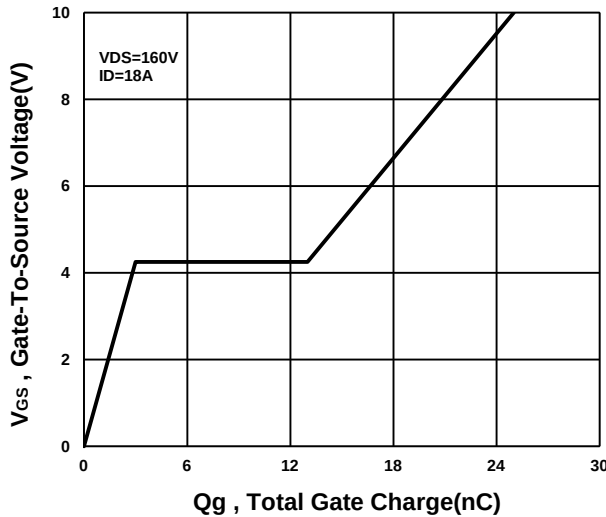
Output Characteristics



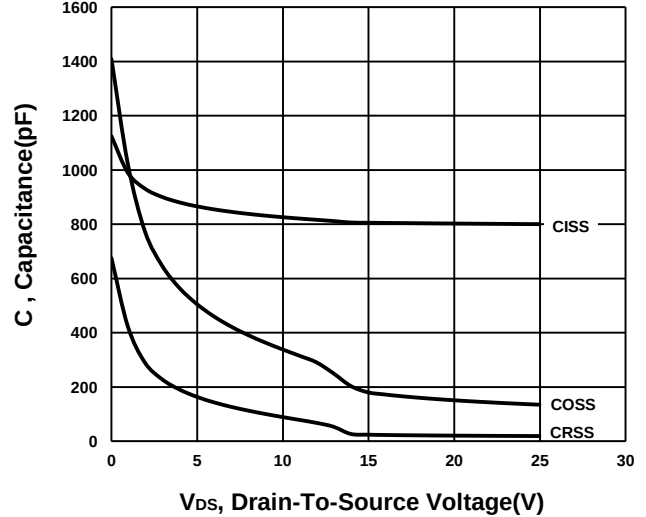
Transfer Characteristics



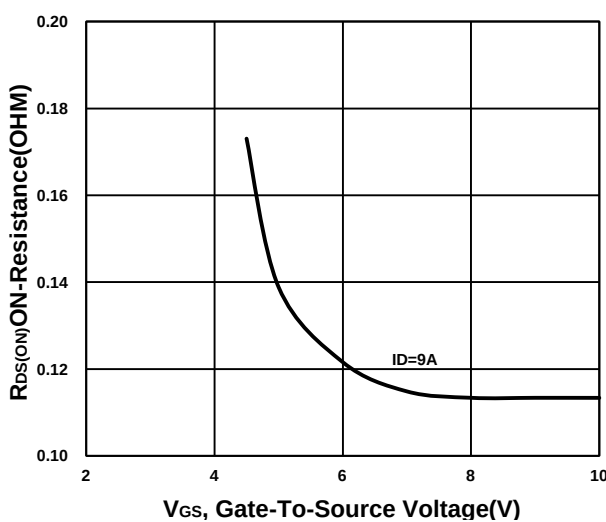
Gate charge Characteristics



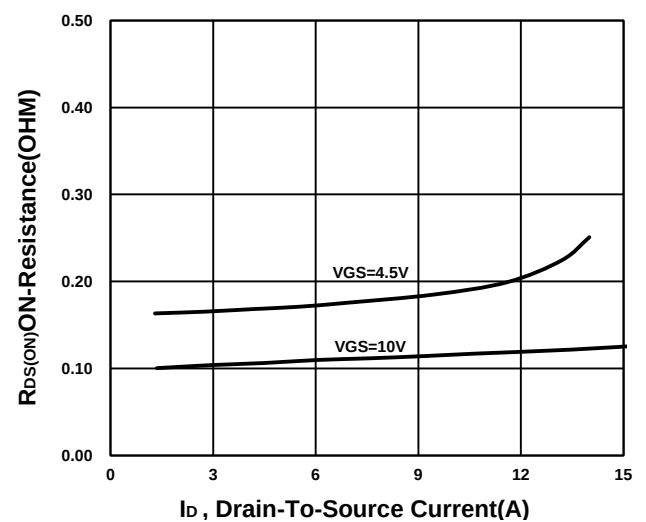
Capacitance Characteristic



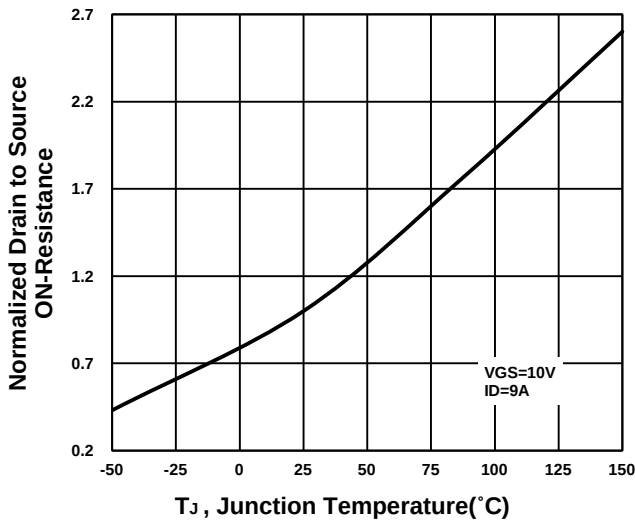
On-Resistance VS Gate-To-Source



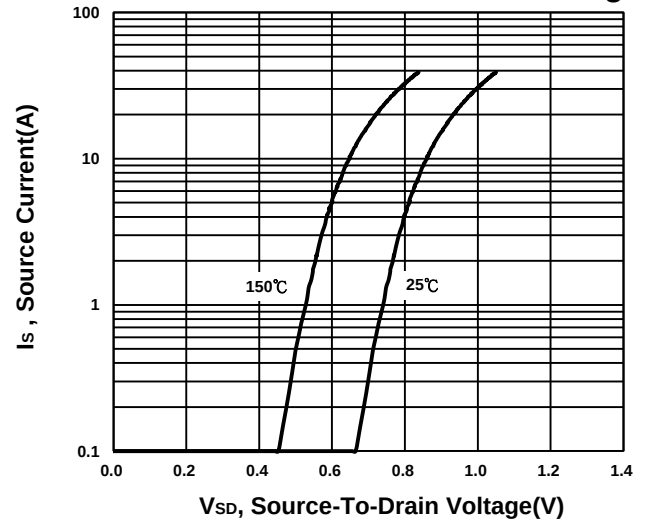
On-Resistance VS Drain Current



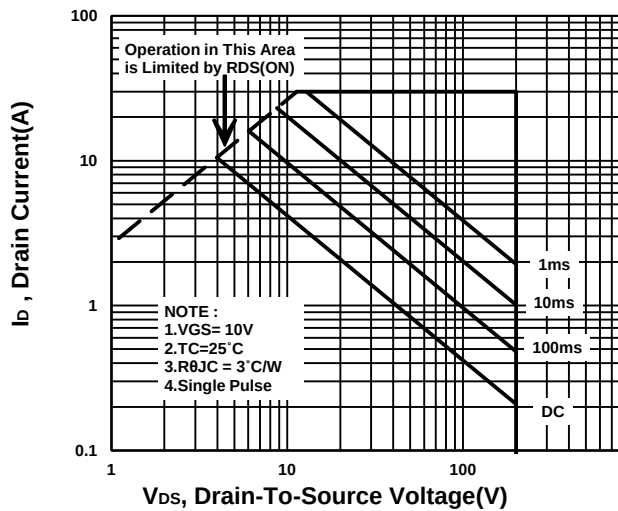
On-Resistance VS Temperature



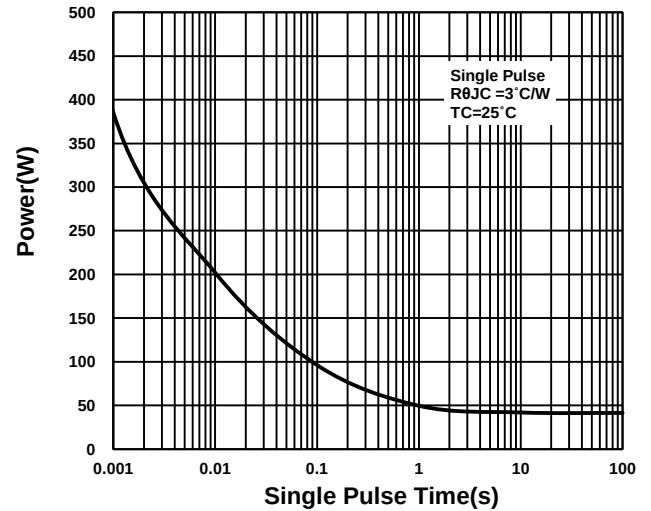
Source-Drain Diode Forward Voltage



Safe Operating Area



Single Pulse Maximum Power Dissipation



Transient Thermal Response Curve

